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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/613,624	07/03/2003	Takashi Mizuno	09792909-5653	4347	
26263	7590 04/20/2005		EXAM	EXAMINER	
SONNENSCHEIN NATH & ROSENTHAL LLP P.O. BOX 061080			DANG, T	DANG, TRUNG Q	
	RIVE STATION, SEARS	TOWER	ART UNIT	PAPER NUMBER	
CHICAGO,	IL 60606-1080		2823		
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Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)	
Office Author Occurred	10/613,624	MIZUNO ET AL.	
Office Action Summary	Examiner	Art Unit	
	Trung Dang	2823	
The MAILING DATE of this communication appeared for Reply	ppears on the cover sheet w	ith the correspondence address	
A SHORTENED STATUTORY PERIOD FOR REP THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR 1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a re - If NO period for reply is specified above, the maximum statutory perior - Failure to reply within the set or extended period for reply will, by statu. Any reply received by the Office later than three months after the mail earned patent term adjustment. See 37 CFR 1.704(b).	. 136(a). In no event, however, may a ply within the statutory minimum of this d will apply and will expire SIX (6) MOI ate, cause the application to become A	reply be timely filed ty (30) days will be considered timely. NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).	
Status			
1)	is action is non-final. ance except for formal mat	·	
Disposition of Claims			
4) ⊠ Claim(s) 1-10 is/are pending in the application 4a) Of the above claim(s) is/are withdrest is/are allowed. 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) 1-10 is/are rejected. 7) □ Claim(s) is/are objected to. 8) □ Claim(s) are subject to restriction and are	awn from consideration.		
Application Papers			
9) ☐ The specification is objected to by the Examin 10) ☑ The drawing(s) filed on 03 July 2003 is/are: a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correction of the 11.	a)⊠ accepted or b)□ obje te drawing(s) be held in abeya ection is required if the drawing	nce. See 37 CFR 1.85(a). g(s) is objected to. See 37 CFR 1.121(d).	i.
Priority under 35 U.S.C. § 119			
a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the priority docume application from the International Bure * See the attached detailed Office action for a list	nts have been received. nts have been received in a iority documents have been eau (PCT Rule 17.2(a)).	Application No received in this National Stage	
Attachment(s)			
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/0 Paper No(s)/Mail Date 	Paper No	Summary (PTO-413) (s)/Mail Date Informal Patent Application (PTO-152) 	

DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kiely et al. (US 5,953,355) in view of Uemura et al. of record.

Kiely teaches method of manufacturing a semiconductor device including a laser chip and a base having the laser chip mounted thereon, including the step of: providing an assembly 10 with the laser chip 20 mounted on the base 12, the assembly including a wire-bonded wiring 22, 24 (see Fig. 1).

Kiely differs from the claims in not disclosing that the assembly having the laser chips mounted on the base is irradiated with an energy beam having a shorter wavelength than an oscillation wavelength of the laser chip to remove adherent from the laser chip and the base.

Uemura et al. teach that when a semiconductor including laser chip is

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irradiated with an energy beam having a shorter wavelength than an oscillation wavelength of the laser chip, organic contaminants adhere on the laser chip is removed. Furthermore, after the wafer is cut into chips, the chips are irradiated with UV rays, hence the reliability of ball bonding is improved (paragraph [0021], paragraph [0070]). See paragraph [0031] for the group III nitride compound semiconductor device includes a laser diode, i.e, the semiconductor chip is a laser chip. Also see paragraph and [0017] for the irradiating UV ray having wavelength of 172 nm, which is a shorter wavelength than an oscillation wavelength of the laser chip (Xe excimer laser lamp light generates UV ray having wavelength of 172 nm).

The subject matter as a whole would have been obvious to one of ordinary skill in the art to modify the teaching of Kiely by irradiating the laser chip 20 mounted on the base 12 depicted in Fig. 1 with UV ray as suggested by Uemura because the UV ray irradiating would remove contaminations adhere on the laser chip therefore preserving the long life as well as the light emission efficiency of the device. Furthermore, in light of Uemura's suggestion that the UV ray irradiating also improves the reliability of ball bonding, it is reasonably expected that such irradiation would also improve the bonding of wires 22, 24 to the chip and the base. Note that when the laser chip mounted on the base is irradiated, the

base is also irradiated.

For claim 2, it is obvious that semiconductor devices are sealed off from the surrounding environment after manufacture in order to protect and to put the devices in practical use. Such practice is conventional as shown in Fig. 1, wherein laser chip 20 are sealed off by surround can 14 and cap 16.

For claim 3, see paragraph [0030].

For claim 4, it is inherent that the laser chip of Uemura et al. would have an oscillation wavelength of 550 nm or less because, like the present invention, it is manufactured using nitride semiconductor layers.

For claim 5, excimer lamp in the reference is a Xe excimer laser lamp light that generates UV ray having wavelength of 172 nm.

As for claims 6, although Uemura et al. disclose an energy beam (UV ray) treatment method, Uemura et al. also disclose that conventional oxygen plasma treatment method is feasible but the oxygen plasma treatment requires controlling the treatment time exactly (paragraph [0021]). The subject matter as a whole would have been obvious to one of ordinary skill in the art to irradiate the base having a laser chip mounted thereon with oxygen plasma because it is recognized that irradiating the chip with oxygen plasma is also applicable but merely requires exact control of the irradiation time.

For claims 7-10, see the above references to claims 2-5, respectively.

Response to Arguments

3. Applicant's arguments filed 04/04/05 with respect to claims 1-10 have been considered but are moot in view of the new ground(s) of rejection.

In the Remarks, applicants argue that Uemura fails to disclose or suggest irradiating a laser chip and body after bonding a wire. Applicants' argument is found unpersuasive for the following reason:

It is Kiely's reference, not Uemura, that is relied in the rejection to show the laser chip 20 mounted on the base 12 and bonding wires 22, 24. The deficiency in Kiely is cured the teaching of Uemura as mentioned in the rejection.

Applicants' argument is therefore largely directed to what the cited references teach individually where the rejection, as here, is based on a combination of references. However, it is axiomatic that one cannot show nonobviousness by attacking references individually. *In re Keller*, 642 F.2d 413, 208 USPQ 871 (CCPA 1981); *In re Merck & Co.*, 800 F.2d 1091, 231 USPQ 375 (Fed. Cir. 1986).

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Trung Dang whose telephone number is

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571-272-1857. The examiner can normally be reached on Mon-Friday 9:30am-

6:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the

examiner's supervisor, Olik Chaudhuri can be reached on 571-272-1855. The fax

phone number for the organization where this application or proceeding is assigned

is 703-872-9306.

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direct.uspto.gov. Should you have questions on access to the Private PAIR system,

contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Trung Dang

Primary Examiner

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04/15/05